

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/577,225 KATATA ET AL.	
		Examiner	Art Unit KEZHEN SHEN	2627      Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,108,291 A	08-2000	Ono et al.	369/47.11
*	B	US-6,263,152 B1	07-2001	Hisatomi et al.	386/243
*	C	US-2003/0059205 A1	03-2003	Suzuki, Ryoichi	386/94
*	D	US-2003/0137909 A1	07-2003	Ito et al.	369/47.14
*	E	US-2003/0179669 A1	09-2003	Takahashi et al.	369/47.14
*	F	US-2003/0193859 A1	10-2003	Mitsuda et al.	369/47.13
*	G	US-2004/0042370 A1	03-2004	Sugimura et al.	369/059.25
*	H	US-7,031,239 B2	04-2006	Takahashi et al.	369/47.14
*	I	US-2006/0171281 A1	08-2006	Takahashi et al.	369/053.17
*	J	US-2006/0171282 A1	08-2006	Takahashi et al.	369/053.17
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	I					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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